

IN THE CLAIMS:

Please amend claims 4-5 as follows:

1-3. (Cancelled)

4. (Currently Amended) A method for correcting [[an]] inter-pin spotting amount errors of a microarray produced by repeating an operation of simultaneously spotting a plurality of groups of samples on a support by using a spotting device provided with a plurality of pins, the method comprising the steps of:

simultaneously spotting the same an identical sample[[s]] as controls onto a group of control spots on the support containing said inter-group spotting amount errors with all of the pins of the spotting device in a predetermined positional relationship, where a plurality of samples are spotted on the support with the spotting device;

measuring spotting amounts [[of]] in the control[[s]] spots spotted with the respective pins of the spotting device to obtain correction parameters for said inter-pin spotting amount errors;

having the plurality of pins of the spotting device capture different samples and simultaneously spotting the different samples captured by the plurality of pins of the spotting device to provide other groups of sample spots on the support in the same predetermined positional relationship with each other as said group of control spots thereby containing said inter-group spotting amount errors; and

correcting an inter-pin spotting amount error measured value of each sample spot of said other groups on the support by using the obtained correction parameters for the inter-pin spotting amount errors.

5. (Currently Amended) A method for correcting an inter-pin spotting amount error of a microarray according to claim 4, wherein information for identifying the pins used for immobilizing spotting [[the]] samples are corresponded to respective sample spots locations on the microarray by is obtained via positional information of wells on [[a]] well plates, which store the samples to be transferred to a microplate the microarray with the pins.

6-10. (Cancelled)